

Notice of References Cited	Application/Control No. 10/741,824	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner John M. Parker	Art Unit 2823	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,573,179	06-2003	Wang et al.	438/652
*	B	US-6,734,559	05-2004	Yang et al.	257/751
*	C	US-6,203,613	03-2001	Gates et al.	117/104
*	D	US-6,518,167	02-2003	You et al.	438/622
*	E	US-6,358,849	03-2002	Havemann et al.	438/689
*	F	US-6,204,168	03-2001	Naik et al.	438/638
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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